WHAT IS CLAIMED IS:

1. A method of detecting a disc defect comprising the steps of:

writing a first data track to the disc with a write head including a write element and a thermal asperity detector;

detecting magnetic defects on the first data track with a certification head; and

scanning the first data track for thermal asperities with the thermal asperity detector.

2. The method of claim 1, further including the steps of:

writing a second data track to the disc;

detecting magnetic defects on the second data track; and

scanning the second data track for thermal asperities.

3. The method of claim 1, further including the step of:

upon locating a thermal asperity during the step of scanning, writing a burst pattern to the disc in a location where a thermal asperity is detected wherein the burst pattern is detectable in further analysis of the disc.

4. A method of detecting magnetic and thermal asperities on a disc comprising the steps of:

writing a first data stream to a first wide track on the disc with a write head located on a write head;

reading the first data stream on a first portion of the first wide track for magnetic defects with a read element located on a certifier head; and

scanning the first wide track for thermal asperities with a thermal asperity detector located on the write head.

5. The method of claim 4, further including the steps of:

writing a second data stream to a second wide track on the disc with the write element;

reading the second data stream on a second portion of the second wide track for magnetic defects with the certifier head; and

scanning the second wide track for thermal asperities with the thermal asperity detector.

6. The method of claim 4, further including the step of:

upon locating a thermal asperity during the step of scanning, writing a burst pattern to the disc in a location where a thermal asperity is detected wherein the burst pattern is detectable in further analysis of the disc.

7. The method of claim 4, further including the step of :

stopping writing of the first data stream on the first wide track while reading the first data stream on a portion of first wide write track.

8. A testing system comprising:

a disc drive having a spindle on which a disc can be mounted and motor for rotating the disc; and

means for detecting thermal asperities and magnetic defects.

9. The testing system of claim 8, wherein the means for detecting thermal asperities is fabricated from magnetic material.

10. The testing system of claim 8, wherein the means for detecting thermal asperities is fabricated from nickel.

11. The testing system of claim 8, wherein the means for detecting thermal asperities is fabricated from a material picked from a group consisting of nickel, beryllium and nickel-iron.

12. The testing system of claim 8, wherein the means for detecting thermal asperities has a width ranging from 10 microns to 100 microns.

13. A testing system for detecting thermal asperities and magnetic defects on a disc comprising:

a write head including a write element, the write head located on a first support arm wherein the write element is activated to write a track onto the disc during a first period;

a thermal asperity detector, wherein the asperity detector is activated to detect asperities during a second period; and

a read head located on a second support arm wherein the read head is positioned to read the track written by the write element.

14. A testing system for detecting thermal asperities and magnetic defects on a disc comprising:

a write head including a write element and a thermal asperity detector, the write head located on a first support arm wherein the write element is activated to write a track onto the disc during a first period and the asperity detector is activated to detect asperities during a second period; and

a read head located on a second support arm wherein the read head is positioned to read the track written by the write element.

15. The testing system of claim 14 wherein the thermal asperity detector is fabricated from a non-magnetic material.

16. The testing system of claim 14 wherein the thermal asperity detector is fabricated from a material picked from a group consisting of nickel, beryllium and nickel-iron.

17. The testing system of claim 14 wherein the thermal asperity detector has a width ranging from about 10 microns to 100 microns.

18. The testing system of claim 14, wherein the thermal asperity detector is fabricated from nickel.

19. The testing system of claim 14, wherein the width of the write head is from about 20 microns to 100 microns.

20. The testing system of claim 17, wherein the width of the write head is about 75 microns.

21. The testing system of claim 14, wherein the write element has a first width and the read element has a second width and a ratio of the first width to the second width is from 2 to 11.